



#### Overview of NEMSIC project: low power integrated sensing with Nano-Electro-Mechanical devices

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#### Outline

- Objectives, partnership and ambition.
- Technology and devices:
  - Thin film SOI NEMS resonators for integrated low power sensing.
  - Functionalization of silicon-based sensors.
  - Power management with NEM-FETs.
- Technical progress: status and highlights.
- Conclusions and perspectives

#### **NEMSIC** objectives

#### Hybrid Nano-Electro-Mechanical / Integrated Circuit Systems for Sensing and Power Management

- Technological objectives
- Sensor and device objectives
- NEM-CMOS application objectives



#### **Technological objectives**

- TO1: Development and validation of a NEM) technology platform for both sensing and power management applications, at CEA-LETI.
- **TO2**: Combination of NEM silicon nanowires device with CMOS in true hybrid technological demonstrators.
- **TO3**: Fast prototyping for Movable-Gate FET operated in power management applications.
- TO4: Technology for functionalized layers and their integration on the NEM technology platform on movable NEM gate or insulator levels, dedicated to gas and bio-molecule sensing.

#### **Sensor objectives**

- **SDO1:** Design and fabrication of dedicated NEM sensors for gas sensing based on vibrating structures able to push the sensitivity to extreme values.
- **SDO2**: Design and fabrication of dedicated Bio-NEM sensors.
- SDO3: Design and fabrication of power management (sleep transistor) NEM-FET switch.

#### **System objectives**

- SYSO1: Realization of a full hybrid sensor/CMOS interface low power smart sensor systems exploiting NEM resonant arrays for gas (COx, NOx, SOx) sensing.
- **SYSO2:** Realization and experimental validation of a Bio-NEMS system for real-time measurements of analytes such as DNA or proteins.
- **SYSO3:** Experimental benchmarking of power savings at circuit and system level by use sleep NEM-FET transistor with reliable operation.

## Partnership

- **EPFL**, Switzerland
- TUD, The Netherlands
- IMEC-NL, The Netherlands
- **SOU**, United Kingdom
- **CEA-LETI**, France
- **SCIPROM**, Switzerland
- IMEC, Belgium
- HON, Romania
- UNIGE, Switzerland replaced by HiQScreen.

#### **WP1: highlights**

 Effects of functionalisation on the conductance of SiNW sensor devices (SOU, IMEC-BE)

NH<sub>2</sub> Self-assembled Monolayer (NH<sub>2</sub> SAM) + Glutaraldehyde(GA) + Biotin



NH<sub>2</sub> SAM coating

#### **Functionalisation: conductance decreased**



## **WP1: highlights**

 Development of selective functionalisation technology on SiNW devices:

 $_{\odot}$  Functionalisation on SiO<sub>2</sub> surface for bio-sensing (IMEC-BE)  $_{\odot}$  Functionalisation on Si-H surface for gas sensing (IMEC-NL)



- Only NWs were decorated by Au NPs (15 nm)
- Amino functionality is only on the NWs

S. Armini., Invited Talk at Annual Meeting of COST Action MP0802

#### **WP1: highlights**

 Selective surface functionalization on <u>suspended</u> Si NWs (IMEC-NL, CEA-LETI, SOU)



SEM characterization of the Si NWs after ebeam selective  $NH_2SAMs$  functionalization followed by Au NPs decoration of the  $NH_2$  groups.

#### **WP2: highlights**

 Hybrid FEA based optimization of FD SOI NEMFET: feedback to fabrication platform and tapeout by EPFL.

|                              | symbol                             | Min. Value | Target | Max. Value | Unit         |
|------------------------------|------------------------------------|------------|--------|------------|--------------|
| SOI thickness                | t <sub>SOI</sub>                   |            | 30     |            | nm           |
| Buried Oxide thickness (BOX) | t <sub>BOX</sub>                   |            | 145    |            | nm           |
| HfO <sub>2</sub> thickness   | t <sub>ox</sub>                    |            | 3      |            | nm           |
| Gap                          | g                                  | 10         |        | 50         | nm           |
| Gate length – beam width     | L <sub>ch</sub> =w <sub>beam</sub> | 150        |        | 600        |              |
| Beam length                  | l <sub>beam</sub>                  | 150        |        | 50000      | n <b>h</b> m |
| Gate thickness (TiN+poly-Si) | tgate                              |            | 110    |            | nm           |
| Beam anchors minimum         |                                    |            | 2      |            | μm           |
| dimensions                   |                                    |            |        |            |              |





## **WP2: highlights**

- Implementation of the compact model for the Fully Depleted SOI NEMFET based on the Berkeley's BSIM Independent Multiple Gate (IMG) compact model for double-gate (independent gate) devices.
- Complete parameter extraction of the FD NEMFET compact model performed for a complete design space exploration.
- First version of the Agilent ADS
   Design Kit (DK) based on the Verilog A compact model for FD SOI NEMFET
   was released



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## **WP2: highlights**

Power components, energy and the energy-delay product for 3 major design implementations:

- Reference
- Hybrid
- Leakage-enhanced

NEMFET low leakage power offers a 2.75x advantage in the OFF power over the classic high-VT transistors.



| Implementation<br>type | ON power<br>[mW] | OFF power [nW] |                     |       | Power-up       | Total          | Energy-                     |
|------------------------|------------------|----------------|---------------------|-------|----------------|----------------|-----------------------------|
|                        |                  | STs            | Always-<br>on cells | Total | energy<br>[pJ] | energy<br>[µJ] | Delay<br>Product<br>[µJ·ns] |
| Reference              | 5.0340           | 56.28          | 26.02               | 81.28 | 48.04          | 9.05           | 62.01                       |
| Hybrid                 | 5.0339           | 4.52           | 26.02               | 29.52 | 37             | 8.61           | 56.47                       |
| Leakage-<br>Enhanced   | 4.7              | 4.52           | 0.364               | 4.884 | 37             | 8              | 51.48                       |

| Table 1 – Pow | ver, energy a | nd energy-d | elay results |
|---------------|---------------|-------------|--------------|
|---------------|---------------|-------------|--------------|

Active time = 1.73 ms, Idle time = 993.35 ms, Transition time = 5.32 ms @ 150 MHz

*Always-on cells* = *Power management controller and isolation cells* 

### **WP3: highlights**

#### 2MHz MEMS Oscillator design and validation (IMEC-NL)



## **WP3: highlights**

 VB-FET small signal model experimentally calibrated and specific features (phase shift and gain) captured in model (EPFL, IMEC-NL) able to serve CMOS-NEMS circuit design



#### **WP4: highlights**

• Investigation by IMEC-BE of nanoscale forces relevant for the designed devices (SiO2 plates): VdW relevant.

 Compare with estimated electrostatic force/area in FD SOI NEMFETs: 0.03-0.3 nN/µm<sup>2</sup>



## **WP4: highlights**

 Successful mixer lock-in amplifier measurement setup by EPFL to avoid the effect of parasitic feedthrough capacitance, enabling high frequency measurements in vibrating nanostructures.



## Highlight WP4 & demo: RF front-end receiver based on RB- FinFETs



Frequency selective demodulation of audio signal using the array of RB-FinFETs is successfully demonstrated

This work is submitted to ISSCC 2012



## WP5: highlights - prototyping

Vibrating body FET of EPFL operating from weak to strong inversion with sub-nW power consumption demonstrated and reported at IEDM 2010. 1E-6  $\frac{1}{1}$   $\frac{1}{1}$ 







# WP5: highlights – techno platform

#### Technology platform for NEMS-CMOS devices @ CEA-LETI:

- Finalization of NEMS device fabrication on both sensor and power management platforms: no further delay in the project due to highly prioritized technology processing at LETI, in line with the new DOW.
- Compatibility with CMOS ICs fully proven experimentally
- High frequency resonator sensors functional in various designs: publications to follow!
- NEM-FET switch fabricated, basic functionality but high leakage, characterization work in progress

## **WP5: highlights**

- Fully functional NEM resonators: cross-beam (CEA-LETI).
- Also experimental demonstrator at the 3rd review.



### WP5: highlights Y3



Vibrating Body FET (VBFET)





Fabricated designs: - EPFL - SOU Collaborative design platform implemented by CEA-LETI



LSGFET



#### **Conclusion and Roadmap**

- The NEMSIC project made significant progress towards both low power integrated sensing and power management objectives
- NEMSIC contributed to establish a new application roadmap for integrated NEM sensors and power management.

